DW PACKAGE

SLIS027A - OCTOBER 1994 - REVISED OCTOBER 1995

- Low r_{DS(on)} . . . 0.4 Ω Typ
- Voltage Output . . . 60 V
- Input Protection Circuitry . . . 18 V
- Pulsed Current . . . 3 A Per Channel
- Extended ESD Capability . . . 4000 V
- Direct Logic-Level Interface

description

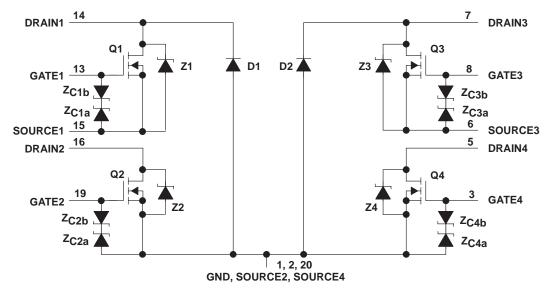
The TPIC5421L is a monolithic gate-protected logic-level power DMOS array that consists of four electrically isolated N-channel enhancement-mode DMOS transistors, two of which are configured with common source. Each transistor features integrated high-current zener diodes ($Z_{\rm CXa}$ and $Z_{\rm CXb}$) to prevent gate damage in the event that an overstress condition occurs. These zener diodes also provide up to 4000 V of ESD protection when tested using the human-body model of a 100-pF capacitor in series with a 1.5-k Ω resistor.

The TPIC5421L is offered in a 20-pin wide-body surface-mount (DW) package and a 16-pin thermally-enhanced dual-in-line (NE) package and is characterized for operation over the case temperature of -40°C to 125°C.

(TOP VIEW) 20 SOURCE2/GND **GND** 19 GATE2 SOURCE4/GND 18 NC GATE4 □ 17 NC NC II 4 DRAIN4 II 5 16 DRAIN2 SOURCE3 [15 SOURCE1 DRAIN3 7 14 DRAIN1 GATE3 8 13 GATE1 12 NC NC II 9 NC 10 11 NC **NE PACKAGE** (TOP VIEW) DRAIN2 16 SOURCE1 SOURCE2/GND [15 DRAIN1 GATE2 3 14 GATE1 13 GND GND [GND [5 12 ∏ GND GATE4 11 GATE3 SOURCE4/GND [10 DRAIN3 DRAIN4 9 SOURCE3

NC - No internal connection

schematic



NOTE A: For correct operation, no terminal may be taken below GND. Pin numbers shown are for the DW package.

TPIC5421L H-BRIDGE GATE-PROTECTED LOGIC-LEVEL POWER DMOS ARRAY

SLIS027A - OCTOBER 1994 - REVISED OCTOBER 1995

absolute maximum ratings over operating case temperature range (unless otherwise noted)[†]

Drain-to-source voltage, V _{DS}	60 V
Source-to-GND voltage (Q1, Q3)	
Drain-to-GND voltage (Q1, Q3)	100 V
Drain-to-GND voltage (Q2, Q4)	60 V
Gate-to-source voltage range, V _{GS}	–9 V to 18 V
Continuous drain current, each output, T _C = 25°C: NE package	1.5 A
	1 A
Continuous source-to-drain diode current, T _C = 25°C	1 A
Pulsed drain current, each output, I _{max} , T _C = 25°C (see Note 1 and Figure 15)	3 A
Continuous gate-to-source zener-diode current, T _C = 25°C	±50 mA
Pulsed gate-to-source zener-diode current, T _C = 25°C	±500 mA
Single-pulse avalanche energy, E_{AS} , $T_{C} = 25^{\circ}C$ (see Figures 4 and 16)	180 mJ
Continuous total power dissipation	See Dissipation Rating Table
Operating virtual junction temperature range, T _{.J.}	–40°C to 150°C
Operating case temperature range, T _C	–40°C to 125°C
Storage temperature range, T _{Stq}	
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: Pulse duration = 10 ms, duty cycle = 2%

DISSIPATION RATING TABLE

PACKAGE	T _C ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _C = 25°C	T _C = 125°C POWER RATING
DW	1125 mW	9.0 mW/°C	225 mW
NE	2075 mW	16.6 mW/°C	415 mW

electrical characteristics, $T_C = 25^{\circ}C$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT	
V _{(BR)DSX}	Drain-to-source breakdown voltage	$I_D = 250 \mu\text{A},$	$V_{GS} = 0$	60			V	
V _{GS(th)}	Gate-to-source threshold voltage	I _D = 1 mA, See Figure 5	$V_{DS} = V_{GS}$	1.5	1.85	2.2	V	
V(BR)GS	Gate-to-source breakdown voltage	IGS = 250 μA		18			V	
V(BR)SG	Source-to-gate breakdown voltage	I _{SG} = 250 μA		9			V	
V _(BR)	Reverse drain-to-GND breakdown voltage (across D1, D2)	Drain-to-GND curren	t = 250 μA	100			V	
V _{DS(on)}	Drain-to-source on-state voltage	I _D = 1 A, See Notes 2 and 3	$V_{GS} = 5 V$,		0.4	0.475	V	
V _{F(SD)}	Forward on-state voltage, source-to-drain	I _S = 1 A, V _{GS} = 0 (Z1, Z2, Z3, See Notes 2 and 3 ar			0.9	1.1	V	
VF	Forward on-state voltage, GND-to-drain	I _D = 1 A (D1, D2), See Notes 2 and 3			4.6		V	
		V _{DS} = 48 V,	T _C = 25°C		0.05	1		
IDSS	Zero-gate-voltage drain current	$V_{GS} = 0$	T _C = 125°C		0.5	10	0 μΑ	
IGSSF	Forward-gate current, drain short circuited to source	V _{GS} = 15 V,	$V_{DS} = 0$		20	200	nA	
IGSSR	Reverse-gate current, drain short circuited to source	V _{SG} = 5 V,	$V_{DS} = 0$		10	100	nA	
t	Leakage august drain to CND	\/ 49.\/	T _C = 25°C		0.05	1	^	
l _{lkg}	Leakage current, drain-to-GND	V _{DGND} = 48 V	T _C = 125°C		0.5	10	μΑ	
	Chatin duain to account an abote resistance	V _{GS} = 5 V, I _D = 1 A,	T _C = 25°C		0.4	0.475	0	
rDS(on)	Static drain-to-source on-state resistance	See Notes 2 and 3 and Figures 6 and 7	T _C = 125°C		0.65	0.68	Ω	
9fs	Forward transconductance	V _{DS} = 15 V, See Notes 2 and 3 ar	I _D = 0.5 A, nd Figure 9	1.25	1.4		S	
C _{iss}	Short-circuit input capacitance, common source	V _{DS} = 25 V, V _{GS} = 0,			220	275		
C _{oss}	Short-circuit output capacitance, common source				120	150	nΕ	
C _{rss}	Short-circuit reverse-transfer capacitance, common source	f = 1 MHz,	See Figure 11		100	125	pF	

NOTES: 2. Technique should limit $T_J - T_C$ to $10^{\circ}C$ maximum.

source-to-drain and GND-to-drain diode characteristics, $T_C = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS				TYP	MAX	UNIT			
				Z1 and Z3		55					
t _{rr}	Reverse-recovery time			Z2 and Z4		150		ns			
		$I_S = 0.5 A,$	$V_{DS} = 48 \text{ V},$	D1 and D2		200					
		V _{GS} = 0, See Figures 1 and 14	$di/dt = 100 A/\mu s$,	Z1 and Z3		0.06					
Q _{RR}	Q _{RR} Total diode charge			ŭ	arge	, and the second se	Z2 and Z4		0.3		μС
				D1 and D2		0.7					

^{3.} These parameters are measured with voltage-sensing contacts separate from the current-carrying contacts.

TPIC5421L H-BRIDGE GATE-PROTECTED LOGIC-LEVEL POWER DMOS ARRAY

SLIS027A - OCTOBER 1994 - REVISED OCTOBER 1995

resistive-load switching characteristics, $T_C = 25^{\circ}C$

	PARAMETER	1	TEST CONDITIO	NS	MIN	TYP	MAX	UNIT												
^t d(on)	Turn-on delay time					25	50													
td(off)	Turn-off delay time	$V_{DD} = 25 \text{ V}, R_L = 25 \Omega,$	$R_L = 25 \Omega$,	t _{r1} = 10 ns,		20	40													
t _{r2}	Rise time	$t_{f1} = 10 \text{ ns},$	See Figure 2			21	42	ns												
t _{f2}	Fall time]				9	18													
Qg	Total gate charge					3.9	5													
Q _{gs(th)}	Threshold gate-to-source charge	V _{DS} = 48 V,					V _{DS} = 48 V, See Figure 3					1 00			$I_D = 0.5 A,$	$V_{GS} = 5 V$,		0.55	0.8	nC
Q _{gd}	Gate-to-drain charge	occ rigare e				2.5	3.6													
L _D	Internal drain inductance					5		- II												
LS	Internal source inductance					5		nΗ												
Rg	Internal gate resistance					0.25		Ω												

thermal resistance

PARAMETER			TEST CONDITIONS	MIN	TYP	MAX	UNIT
		DW package	Coo Notoo A and C		90		
КθЈА	$R_{ heta JA}$ Junction-to-ambient thermal resistance	NE package	See Notes 4 and 6		60		
$R_{\theta JB}$	Junction-to-board thermal resistance	DW package	See Notes 4 and 6		53		°C/W
D	R _{θJP} Junction-to-pin thermal resistance	DW package	See Notes 5 and 6		30		
KOJP		NE package	See Notes 5 and 6		25		

NOTES: 4. Package mounted on an FR4 printed-circuit board with no heatsink.

5. Package mounted in intimate contact with infinite heatsink.

6. All outputs with equal power

PARAMETER MEASUREMENT INFORMATION

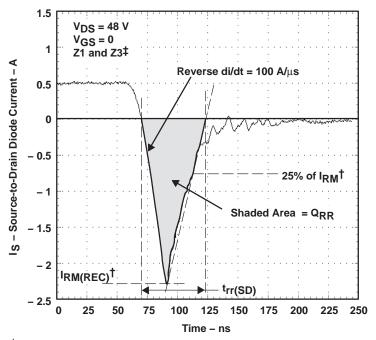
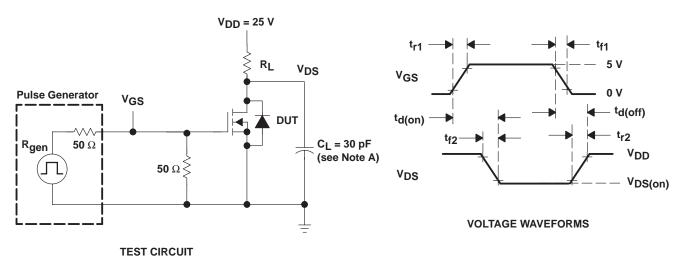


Figure 1. Reverse-Recovery-Current Waveforms of Source-to-Drain Diode



NOTE A: C_L includes probe and jig capacitance.

Figure 2. Resistive-Switching Test Circuit and Voltage Waveforms

 $[\]begin{tabular}{l} \uparrow I_{RM(REC)}$ = maximum recovery current \\ $\rlap/$ The above waveform is representative of Z2, Z4, D1, and D2 in shape only. \\ \end{tabular}$

PARAMETER MEASUREMENT INFORMATION

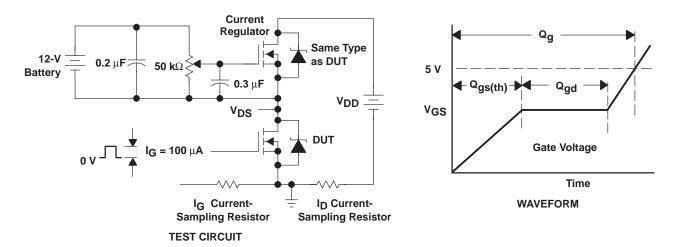
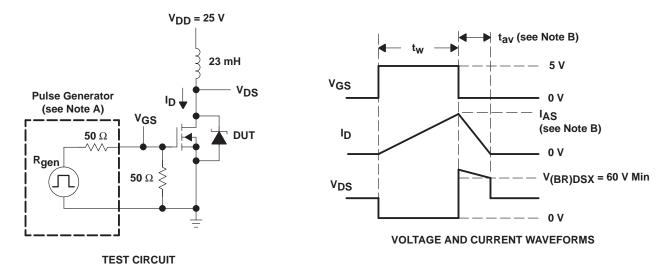


Figure 3. Gate-Charge Test Circuit and Waveform



- NOTES: A. The pulse generator has the following characteristics: $t_{\Gamma} \le 10$ ns, $t_{\Gamma} \le 10$ ns, $t_{\Omega} = 50 \ \Omega$.
 - B. Input pulse duration (t_W) is increased until peak current $I_{AS} = 3$ A.

Energy test level is defined as E_{AS} =
$$\frac{I_{AS} \times V_{(BR)DSX} \times t_{av}}{2}$$
 = 180 mJ, where t_{av} = avalanche time

Figure 4. Single-Pulse Avalanche-Energy Test Circuit and Waveforms

TYPICAL CHARACTERISTICS

GATE-TO-SOURCE THRESHOLD VOLTAGE

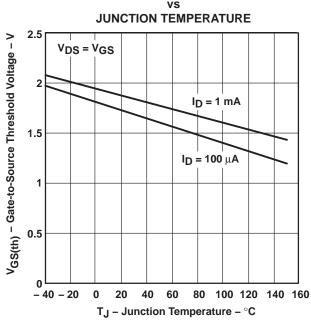


Figure 5

STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

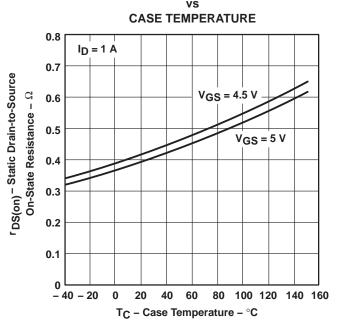


Figure 6

STATIC DRAIN-TO-SOURCE ON-STATE RESISTANCE

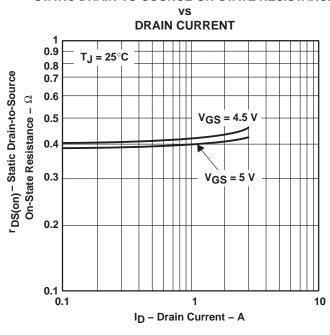


Figure 7

DRAIN CURRENT vs DRAIN-TO-SOURCE VOLTAGE

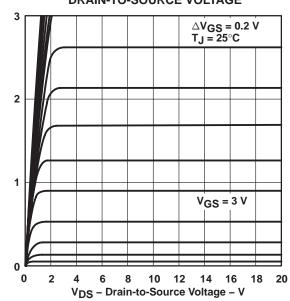


Figure 8

D- Drain Current - A

TYPICAL CHARACTERISTICS

3

2

0

 $T_J = 150^{\circ}C$ $T_J = 125^{\circ}C$

1

ID - Drain Current - A

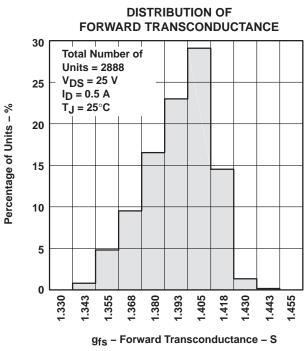


Figure 9

V_{GS} - Gate-to-Source Voltage - V

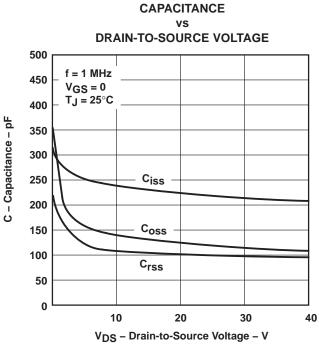
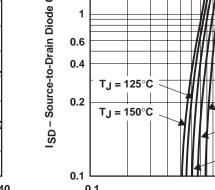


Figure 11



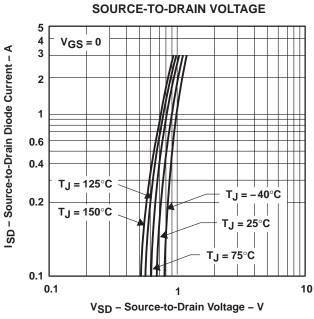


Figure 10

SOURCE-TO-DRAIN DIODE CURRENT

DRAIN CURRENT

GATE-TO-SOURCE VOLTAGE

 $T_J = -40^{\circ}C$

5

TJ = 25°C

 $T_J = 75^{\circ}C$

3

TYPICAL CHARACTERISTICS

DRAIN-TO-SOURCE VOLTAGE AND GATE-TO-SOURCE VOLTAGE

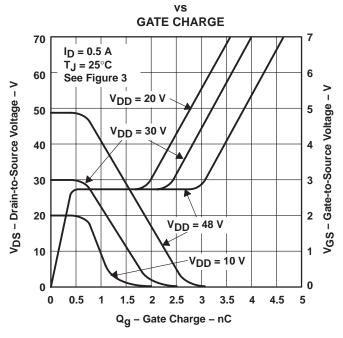


Figure 13

REVERSE-RECOVERY TIME

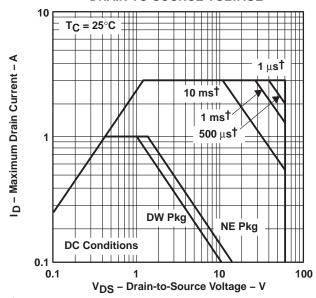
٧S REVERSE di/dt 200 $V_{DS} = 48 V$ $V_{GS} = 0$ 175 $I_{S} = 0.5 A$ trr - Reverse-Recovery Time - ns T_J = 25°C 150 See Figure 1 125 100 Z2 and Z4 75 50 Z1 and Z3 25 0 100 200 300 400 500 700 600 Reverse di/dt - A/µs

Figure 14



THERMAL INFORMATION

MAXIMUM DRAIN CURRENT vs DRAIN-TO-SOURCE VOLTAGE



†Less than 2% duty cycle

Figure 15

MAXIMUM PEAK AVALANCHE CURRENT vs TIME DURATION OF AVALANCHE

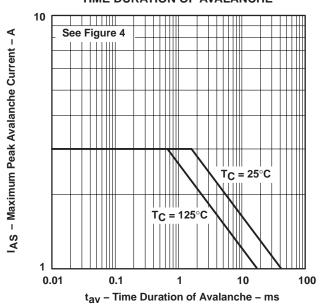
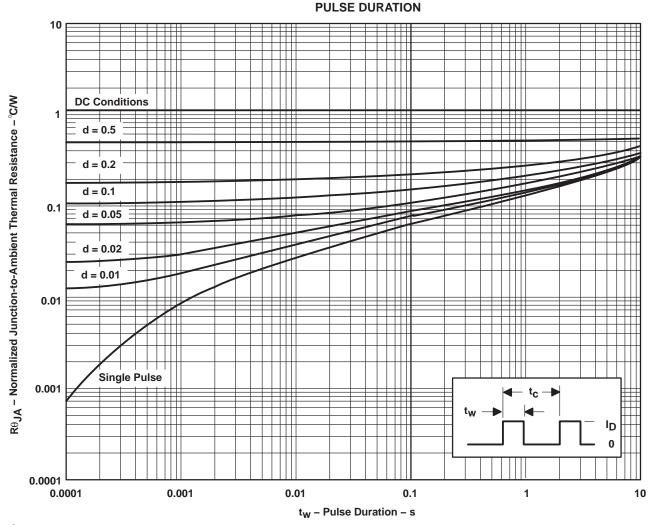


Figure 16

SLIS027A - OCTOBER 1994 - REVISED OCTOBER 1995

THERMAL INFORMATION

NE PACKAGE[†] NORMALIZED JUNCTION-TO-AMBIENT THERMAL RESISTANCE vs



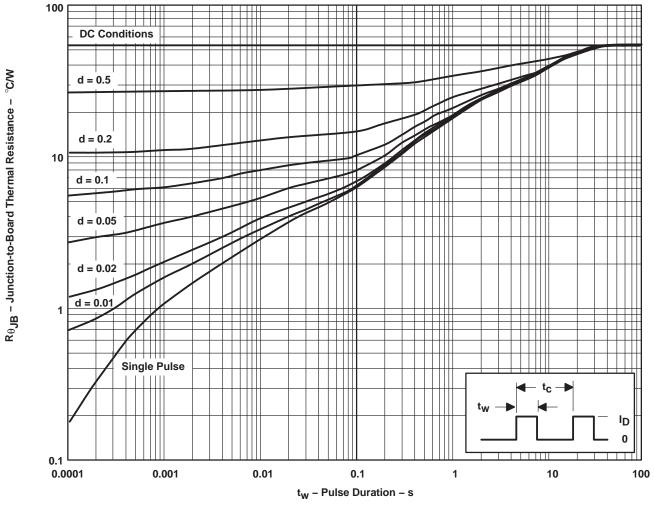
† Device mounted on FR4 printed-circuit board with no heatsink.

NOTES A: $Z_{\theta JA}(t) = r(t) R_{\theta JA}$ $t_W = \text{pulse duration}$ $t_C = \text{cycle time}$ $d = \text{duty cycle} = t_W/t_C$

Figure 17

THERMAL INFORMATION

DW PACKAGE† JUNCTION-TO-BOARD THERMAL RESISTANCE vs PULSE DURATION



† Device mounted on a 24 in², 4-layer FR4 printed-circuit board with no heatsink.

NOTES A: $Z_{\theta JB}(t) = r(t) R_{\theta JB}$ $t_W = \text{pulse duration}$ $t_C = \text{cycle time}$ $d = \text{duty cycle} = t_W/t_C$

Figure 18





PACKAGE OPTION ADDENDUM

8-Apr-2005

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
TPIC5421LDW	OBSOLETE	SOIC	DW	20	TBD	Call TI	Call TI
TPIC5421LNE	OBSOLETE	PDIP	NE	16	TBD	Call TI	Call TI

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in

a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS) or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

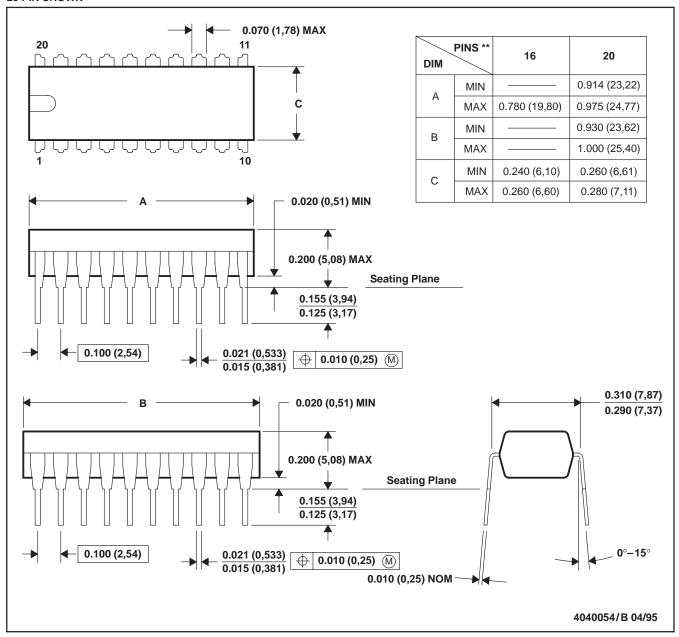
Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

NE (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

20 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

B. This drawing is subject to change without notice.

C. Falls within JEDEC MS-001 (16 pin only)

DW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters). Dimensioning and tolerancing per ASME Y14.5M-1994.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013 variation AC.



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, modifications, enhancements, improvements, and other changes to its products and services at any time and to discontinue any product or service without notice. Customers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All products are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its hardware products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by government requirements, testing of all parameters of each product is not necessarily performed.

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any TI patent right, copyright, mask work right, or other TI intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information published by TI regarding third-party products or services does not constitute a license from TI to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. Reproduction of this information with alteration is an unfair and deceptive business practice. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

TI products are not authorized for use in safety-critical applications (such as life support) where a failure of the TI product would reasonably be expected to cause severe personal injury or death, unless officers of the parties have executed an agreement specifically governing such use. Buyers represent that they have all necessary expertise in the safety and regulatory ramifications of their applications, and acknowledge and agree that they are solely responsible for all legal, regulatory and safety-related requirements concerning their products and any use of TI products in such safety-critical applications, notwithstanding any applications-related information or support that may be provided by TI. Further, Buyers must fully indemnify TI and its representatives against any damages arising out of the use of TI products in such safety-critical applications.

TI products are neither designed nor intended for use in military/aerospace applications or environments unless the TI products are specifically designated by TI as military-grade or "enhanced plastic." Only products designated by TI as military-grade meet military specifications. Buyers acknowledge and agree that any such use of TI products which TI has not designated as military-grade is solely at the Buyer's risk, and that they are solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI products are neither designed nor intended for use in automotive applications or environments unless the specific TI products are designated by TI as compliant with ISO/TS 16949 requirements. Buyers acknowledge and agree that, if they use any non-designated products in automotive applications, TI will not be responsible for any failure to meet such requirements.

Following are URLs where you can obtain information on other Texas Instruments products and application solutions:

Products		Applications	
Audio	www.ti.com/audio	Communications and Telecom	www.ti.com/communications
Amplifiers	amplifier.ti.com	Computers and Peripherals	www.ti.com/computers
Data Converters	dataconverter.ti.com	Consumer Electronics	www.ti.com/consumer-apps
DLP® Products	www.dlp.com	Energy and Lighting	www.ti.com/energy
DSP	dsp.ti.com	Industrial	www.ti.com/industrial
Clocks and Timers	www.ti.com/clocks	Medical	www.ti.com/medical
Interface	interface.ti.com	Security	www.ti.com/security
Logic	logic.ti.com	Space, Avionics and Defense	www.ti.com/space-avionics-defense
Power Mgmt	power.ti.com	Transportation and Automotive	www.ti.com/automotive
Microcontrollers	microcontroller.ti.com	Video and Imaging	www.ti.com/video
RFID	www.ti-rfid.com	Wireless	www.ti.com/wireless-apps
RF/IF and ZigBee® Solutions	www.ti.com/lprf		

TI E2E Community Home Page

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2011, Texas Instruments Incorporated

e2e.ti.com